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June 2016

FCH023N65S3

N-Channel SuperFET[®] III MOSFET 650 V, 75 A, 23 m Ω

Features

- 700 V @ T_J = 150°C
- Typ. $R_{DS(on)}$ = 19.5 m Ω
- Ultra Low Gate Charge (Typ. Q_g = 222 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 1980 pF)
- · 100% Avalanche Tested
- · RoHS Compliant

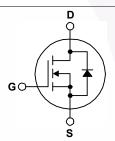
Applications

- Telecom / Server Power Supplies UPS / Solar
- · Industrial Power Supply

Description

SuperFET[®] III MOSFET is Fairchild Semiconductor's brandnew high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate. Consequently, SuperFET III MOSFET is suitable for various DC/AC power conversion for system miniaturization and higher efficiency.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter		FCH023N65S3_F155	Unit
V _{DSS}	Drain to Source Voltage			650	V
V	- DC			±30	V
V_{GSS}	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	V
	Drain Current	- Continuous (T _C = 25°C)		75	Α
ID	Drain Current	- Continuous (T _C = 100°C)		65.8	A
I _{DM}	Drain Current	- Pulsed	(Note 1)	300	Α
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	2025	mJ
I _{AR}	Avalanche Current		(Note 1)	15	Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	5.95	mJ
dv/dt	MOSFET dv/dt			100	V/no
uv/ut	Peak Diode Recovery dv/dt	dv/dt (Note 3)		20	V/ns
D	Payer Dissipation	(T _C = 25°C)		595	W
P_{D}	Power Dissipation - Derate Above 25°C		4.76	W/°C	
T _J , T _{STG}	Operating and Storage Temperat	ure Range		-55 to +150	°C
T _L	Maximum Lead Temperature for 1/8" from Case for 5 Seconds	Soldering,		300	°C

Thermal Characteristics

Symbol	Parameter	FCH023N65S3_F155	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.21	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	C/VV

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCH023N65S3_F155	FCH023N65S3	TO-247 G03	Tube	N/A	N/A	30 units

Test Conditions

Min.

Тур.

Max. Unit

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted. Parameter

•						
Off Chara	acteristics					
D\/	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650	-	-	\/
BV _{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 150^{\circ}\text{C}$	700	-	-	, v
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C	-	0.72	-	V/°C
	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V	-	-	1	
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 520 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	6.8	-	μА
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±30 V, V _{DS} = 0 V	-	-	±100	nA

On Characteristics

Symbol

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 7.5 \text{ mA}$	2.5	-	4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 37.5 \text{ A}$	-	19.5	23	mΩ
9 _{FS}	Forward Transconductance	V_{DS} = 20 V, I_{D} = 37.5 A	-	66	1	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V,	-	7160	-	pF
C _{oss}	Output Capacitance	f = 1 MHz	-	195	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V	-	1980	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	$V_{DS} = 0 V \text{ to } 400 V, V_{GS} = 0 V$	- \	298	-	
Q _{g(tot)}	Total Gate Charge at 10V	V _{DS} = 400 V, I _D = 37.5 A,	-	222	-	nC
Q_{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	54	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	90	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.9	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	45	-	ns
t _r	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, I_D = 37.5 \text{ A},$		- /	55	-	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_g = 2 Ω		-/	140	-	ns
t _f	Turn-Off Fall Time		(Note 4)	-	29	-	ns

Drain-Source Diode Characteristics

Is	Maximum Continuous Drain to Source Dioc	Maximum Continuous Drain to Source Diode Forward Current			75	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	300	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 37.5 A	-	-	1.2	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 37.5 A,	-	600	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	17.9	-	μС

- 1. Repetitive rating: pulse width limited by maximum junction temperature.
- 2. I_{AS} = 15 A, R_{G} = 25 Ω , starting T_{J} = 25°C.
- 3. I_{SD} \leq 75 A, di/dt \leq 200 A/µs, V_{DD} \leq BV_DSS, starting T_J = 25°C.
- 4. Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

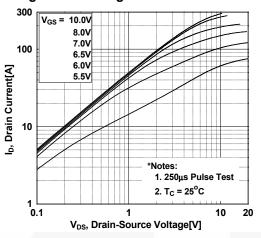


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

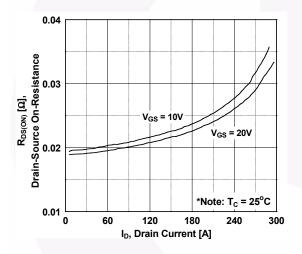


Figure 5. Capacitance Characteristics

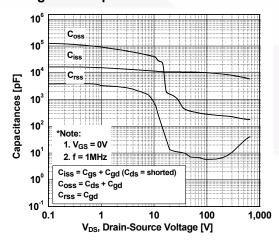


Figure 2. Transfer Characteristics

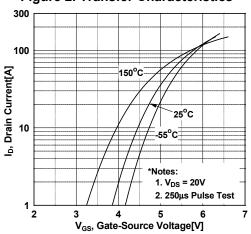


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

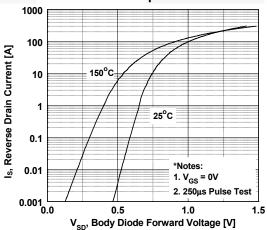
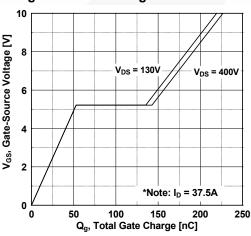


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

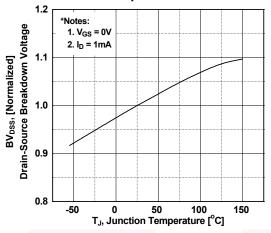


Figure 8. On-Resistance Variation vs. Temperature

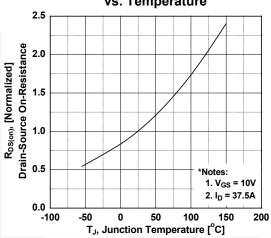


Figure 9. Maximum Safe Operating Area

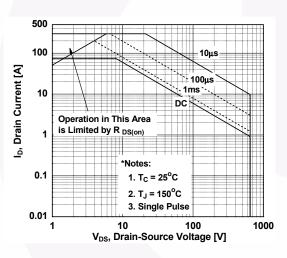


Figure 10. Maximum Drain Current vs. Case Temperature

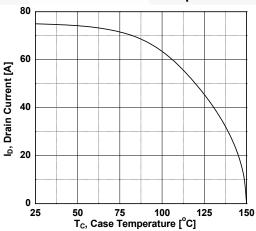
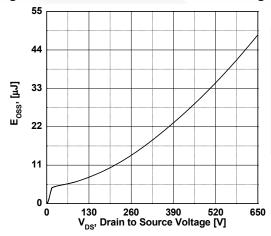
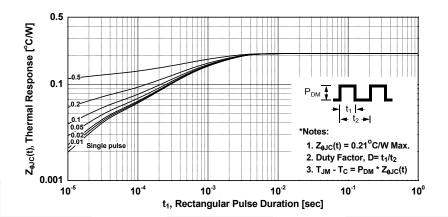


Figure 11. Eoss vs. Drain to Source Voltage



Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve



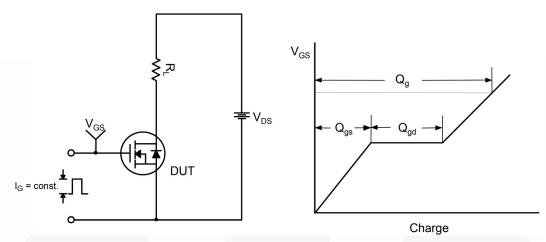


Figure 13. Gate Charge Test Circuit & Waveform

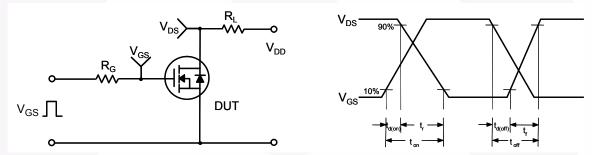


Figure 14. Resistive Switching Test Circuit & Waveforms

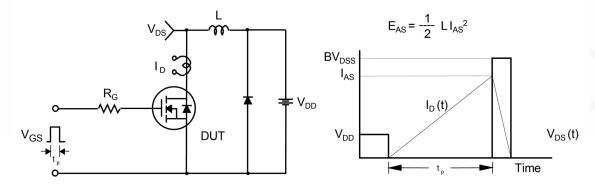


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

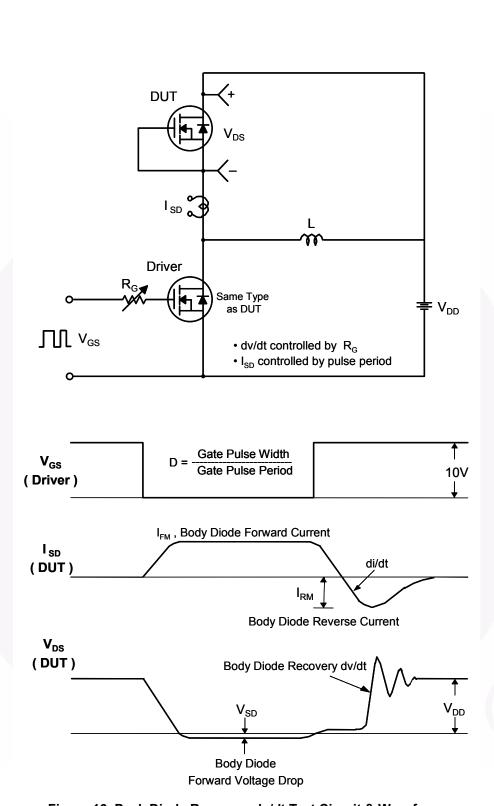
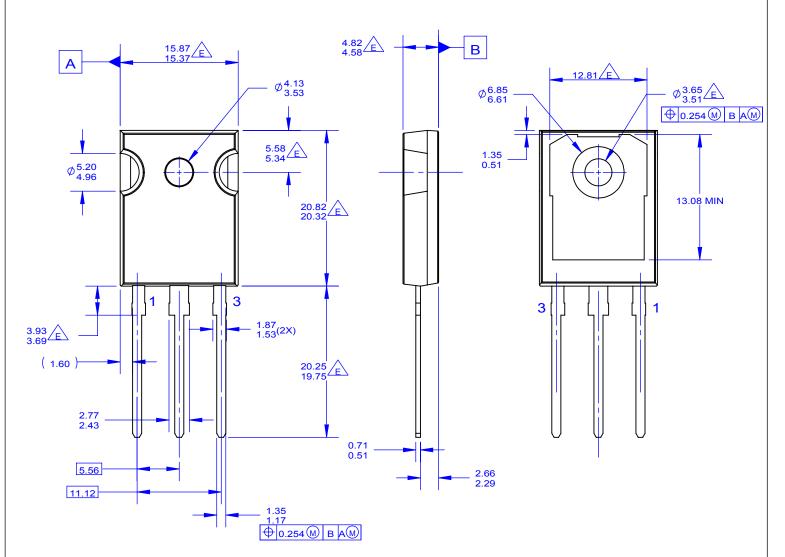


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms



NOTES: UNLESS OTHERWISE SPECIFIED.

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- C. ALL DIMENSIONS ARE IN MILLIMETERS.
- D. DRAWING CONFORMS TO ASME Y14.5 1994





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